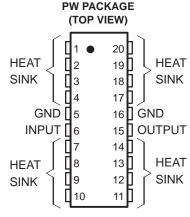
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- Fixed 3.3-V Output
- ±1% Maximum Output Voltage Tolerance at T_{.1} = 25°C
- 500-mV Maximum Dropout Voltage at 500 mA
- 500-mA Dropout Current
- ±2% Absolute Output Voltage Variation
- Internal Overcurrent Limiting
- Internal Thermal-Overload Protection
- Internal Overvoltage Protection
- Package Options Include Plastic Flange Mounted (KTP), Power (KC), and Thin Shrink Small-Outline (PW) Packages

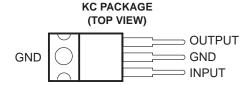
description

The TLV2217-33 is a low-dropout 3.3-V fixed-voltage regulator. The regulator is capable of sourcing 500 mA of current with an input-output differential of 0.5 V, or less. The TLV2217-33 provides internal overcurrent limiting, thermal-overload protection, and overvoltage protection.

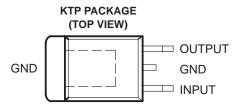
The 0.5-V dropout for the TLV2217-33 makes it ideal for battery applications in 3.3-V logic systems. For example, battery input voltage to the regulator can drop as low as 3.8 V, and the TLV2217-33 can continue to regulate the system. For higher voltage systems, the TLV2217-33 can be operated with a continuous input voltage of 12 V.



HEAT SINK – These terminals have an internal resistive connection to ground and should be grounded or electrically isolated.



The GND terminal is in electrical contact with the mounting base.



The GND terminal is in electrical contact with the mounting base.

The TLV2217-33 regulators are characterized for virtual junction temperature operation from 0°C to 125°C.

AVAILABLE OPTIONS

	PACKAGED DEVICES			
TJ	PLASTIC POWER (KC)	SURFACE MOUNT (PW)	PLASTIC FLANGE MOUNT (KTP)	CHIP FORM (Y)
0°C to 125°C	TLV2217-33KC	TLV2217-33PW	TLV2217-33KTP	TLV2217-33Y

The KTP and PW packages are available taped and reeled only. Add R suffix to device type (e.g., TLV2212-33PWR). Chip forms are tested at 25°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



TLV2217-33 LOW-DROPOUT 3.3-V FIXED-VOLTAGE REGULATORS

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absolute maximum ratings over operating virtual junction temperature range (unless otherwise noted)†

Continuous input voltage, VI		
Package thermal impedance, θ _{JA} (see Notes 1 and 2):	KC package	22°C/\
	KTP package	28°C/\
	PW package	83°C/\
Storage temperature range, Teta		

- NOTES: 1. Maximum power dissipation is a function of T_J(max), θ_{JA}, and T_A. The maximum allowable power dissipation at any allowable ambient temperature is P_D = (T_J(max) T_A)/θ_{JA}. Operating at the absolute maximum T_J of 150°C can impact reliability. Due to variation in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection may be activated at power levels slightly above or below the rated dissipation.
 - 2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

	MIN	MAX	UNIT
Input voltage, V _I	3.8	12	V
Output current, IO	0	500	mA
Operating virtual junction temperature range, T _J	0	125	°C

electrical characteristics at V_I = 4.5 V, I_O = 500 mA, T_J = 25°C (unless otherwise noted)

PARAMETER	TEST CONDITIONS‡			TLV2217-33			UNIT	
PARAMETER				MIN	TYP	MAX	UNIT	
Output voltage	$I_O = 20 \text{ mA to } 500 \text{ mA}, \qquad V_I = 3.8 \text{ V to } 5.5 \text{ V}$	\\. 2.9.\\ to F.F.\\	T _J = 25°C	3.267	3.30	3.333	V	
		$T_J = 0$ °C to 125°C	3.234		3.366	l v		
Input voltage regulation	V _I = 3.8 V to 5.5 V				5	15	mV	
Ripple rejection	f = 120 Hz,	V _{ripple} = 1 V _{PP}			-62		dB	
Output voltage regulation	$I_O = 20 \text{ mA to } 500 \text{ mA}$				5	30	mV	
Output noise voltage	f = 10 Hz to 100 kHz				500		μV	
Dropout voltage	I _O = 250 mA				400	mV		
	I _O = 500 mA					500	IIIV	
Bias current	IO = 0				2	5	mA	
	I _O = 500 mA				19	49		

[‡] Pulse-testing techniques are used to maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 22-μF tantalum capacitor with equivalent series resistance of 1.5 Ω on the output.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

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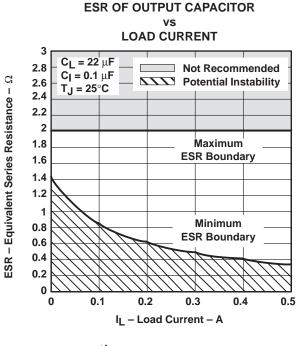
electrical characteristics at V $_{I}$ = 4.5 V, I $_{O}$ = 500 mA, T $_{J}$ = 25 $^{\circ}\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONST		TLV2217-33Y		
PARAMETER	TEST C	CONDITIONS	MIN	TYP	MAX	UNIT
Output voltage	$I_O = 20 \text{ mA to } 500 \text{ mA},$	$V_I = 3.8 \text{ V to } 5.5 \text{ V}$	3.267	3.30	3.333	V
Input voltage regulation	V _I = 3.8 V to 5.5 V			5	15	mV
Ripple rejection	f = 120 Hz,	V _{ripple} = 1 V _{PP}		-62		dB
Output voltage regulation	I _O = 20 mA to 500 mA			5	30	mV
Output noise voltage	f = 10 Hz to 100 kHz			500		μV
Barandarilla	I _O = 250 mA	I _O = 250 mA			400	mV
Dropout voltage	I _O = 500 mA				500	IIIV
Bias current	IO = 0	IO = 0		2	5	m A
	I _O = 500 mA			19	49	mA

[†] Pulse-testing techniques are used to maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 22-μF tantalum capacitor with equivalent series resistance of 1.5 Ω on the output.

COMPENSATION-CAPACITOR SELECTION INFORMATION

The TLV2217-33 is a low-dropout regulator. This means that the capacitance loading is important to the performance of the regulator because it is a vital part of the control loop. The capacitor value and the equivalent series resistance (ESR) both affect the control loop and must be defined for the load range and the temperature range. Figures 1 and 2 can be used to establish the capacitance value and ESR range for best regulator performance.



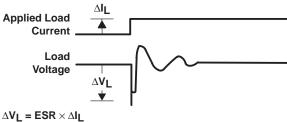


Figure 1

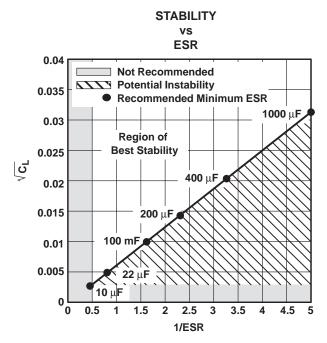


Figure 2



APPLICATION INFORMATION

application schematic

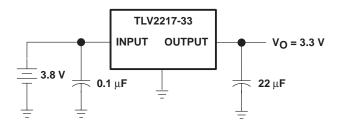


Figure 3

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